

Notice of References Cited	Application/Control No. 10/580,143	Applicant(s)/Patent Under Reexamination SEIDLER ET AL.	
	Examiner Tran N. Nguyen	Art Unit 2834	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,115,040 A	09-1978	Knorr, Manfred	417/420
*	B	US-4,752,194 A	06-1988	Wienen et al.	417/420
*	C	US-4,890,988 A	01-1990	Kramer et al.	417/372
*	D	US-5,017,102 A	05-1991	Shimaguchi et al.	417/420
*	E	US-5,090,944 A	02-1992	Kyo et al.	464/29
*	F	US-6,841,909 B2	01-2005	Six, Albert	310/103
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 08151994 A	06-1996	Japan (abstract)	YANO et al.	F04D 13/02
	O	JP 09268994 A	10-1997	Japan	YANO et al.	F04D 13/02
	P	JP 2002155883 A	05-2002	Japan (abstract)	MIYAKE et al.	F04D 13/02
	Q	JP 2003254280 A	09-2003	Japan	SANO, YOSHIYUKI	F04D 13/02
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.